



Designation: D4417 – 21

# Standard Test Methods for Field Measurement of Surface Profile of Blast Cleaned Steel<sup>1</sup>

This standard is issued under the fixed designation D4417; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reappraisal. A superscript epsilon ( $\epsilon$ ) indicates an editorial change since the last revision or reappraisal.

*This standard has been approved for use by agencies of the U.S. Department of Defense.*

## 1. Scope

1.1 These test methods cover the description of techniques for measuring the profile of abrasive blast cleaned surfaces in the field, shop, and laboratory. There are other techniques suitable for laboratory use not covered by these test methods.

1.2 Method B may also be appropriate to the measurement of profile produced by using power tools.

NOTE 1—The Method B procedure in this standard was developed for use on flat surfaces. Depending on the radius of the surface, the results could have greater variability with lower values and averages.

1.3 SSPC standard SSPC-PA 17 provides additional guidance for determining conformance with surface profile requirements.

1.4 The values stated in SI units are to be regarded as the standard. The values given in parentheses are for information only.

1.5 *This standard does not purport to address all of the safety concerns, if any, associated with its use. It is the responsibility of the user of this standard to establish appropriate safety, health, and environmental practices and determine the applicability of regulatory limitations prior to use.*

1.6 *This international standard was developed in accordance with internationally recognized principles on standardization established in the Decision on Principles for the Development of International Standards, Guides and Recommendations issued by the World Trade Organization Technical Barriers to Trade (TBT) Committee.*

<sup>1</sup> These test methods are under the jurisdiction of ASTM Committee D01 on Paint and Related Coatings, Materials, and Applications and are the direct responsibility of Subcommittee D01.46 on Industrial Protective Coatings.

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## 2. Referenced Documents

### 2.1 ASTM Standards:<sup>2</sup>

**D7127** Test Method for Measurement of Surface Roughness of Abrasive Blast Cleaned Metal Surfaces Using a Portable Stylus Instrument

**E177** Practice for Use of the Terms Precision and Bias in ASTM Test Methods

**E691** Practice for Conducting an Interlaboratory Study to Determine the Precision of a Test Method

### 2.2 SSPC Standard:<sup>3</sup>

**SSPC-PA 17** Procedure for Determining Conformance to Steel Profile/Surface Roughness/Peak Count Requirements

### 2.3 ASME Standard:<sup>4</sup>

**ASME B46.1-2002** Surface Texture, Surface Roughness Waviness and Lay

### 2.4 ISO Standards:<sup>5</sup>

**ISO 4287: 1997** Geometrical Product Specifications (GPS)—Surface Texture: Profile Method—Terms, Definitions, and Surface Parameters

## 3. Terminology

### 3.1 Definitions of Terms Specific to This Standard:

<sup>2</sup> For referenced ASTM standards, visit the ASTM website, [www.astm.org](http://www.astm.org), or contact ASTM Customer Service at [service@astm.org](mailto:service@astm.org). For *Annual Book of ASTM Standards* volume information, refer to the standard's Document Summary page on the ASTM website.

<sup>3</sup> Available from Society for Protective Coatings (SSPC), 800 Trumbull Dr., Pittsburgh, PA 15205, <http://www.sspc.org>.

<sup>4</sup> Available from American Society of Mechanical Engineers (ASME), ASME International Headquarters, Two Park Ave., New York, NY 10016-5990, <http://www.asme.org>.

<sup>5</sup> Available from International Organization for Standardization (ISO), ISO Central Secretariat, BIBC II, Chemin de Blandonnet 8, CP 401, 1214 Vernier, Geneva, Switzerland, <http://www.iso.org>.

3.1.1 *deadband, n*—that distance above and below the mean line that a continuous stylus trace line must cross in both directions (up and down) to count as a single peak.

3.1.2 *evaluation length, n*—a sequence of five consecutive stylus sampling lengths.

3.1.3 *H, n*—the average of the maximum peak-to-valley height distances obtained by measuring the thickness of replica tape.

3.1.3.1 *Discussion*— $H_L$  is the thickness measurement adjusted for tape non-linearity.

3.1.4 *Pd (peak density), n*—the number of peaks per unit area obtained from burnished replica tape.

3.1.5 *peak, n*—a high point in a surface profile.

3.1.6 *Rpc (peak count), n*—the number of peak/valley pairs, per unit of length, extending outside a “deadband” centered on the mean line of a stylus trace.

3.1.6.1 *Discussion*—For the purpose of *Rpc*, a peak is defined relative to an upper and lower height threshold. This is a single number (peak count threshold) and is the distance from a lower threshold to an upper threshold centered on the mean line of the profile.

3.1.7 *Rt, n*—the vertical distance between the highest peak and the lowest valley within any given stylus evaluation length.

3.1.8 *sampling length, n*—the nominal distance parallel to the surface within which surface parameters are determined.

3.1.9 *surface profile, n*—the height of the major peaks relative to the major valleys.

3.1.10 *traversing length, n*—seven sampling lengths comprising the evaluation length and the stylus pre-travel and post-travel segments.

## 4. Summary of Test Method

4.1 The methods are:

4.1.1 *Method A*—The abrasive cleaned surface is compared to commercial replicas of various surface profile depths prepared by different blast media and the range determined. The geometry of the specific abrasive cleaned surface can also be observed.

4.1.2 *Method B*—The depth of profile relative to the peaks is measured using a fine-pointed probe at a number of locations and the average of the maximum peak-to-valley distances (or alternatively, the average peak-to-valley distances) is determined.

4.1.3 *Method C*—A composite plastic tape is impressed into the blast cleaned surface forming a reverse image of the profile. The average maximum peak-to-valley distance can be measured using a suitable thickness gage. The average of these distances can be determined from a group of measurements. Specially designed optical readers can also determine the peak density from the tape replica.

4.1.4 *Method D*—A trace measurement is taken by a portable stylus surface roughness instrument to obtain maximum peak-to-valley distance. The average of these distances is determined from a group of five traces. These devices can also determine peak count information.

## 5. Significance and Use

5.1 The height of surface profile has been shown to be a factor in the performance of various coatings applied to steel. For this reason, surface profile should be measured prior to coating application to ensure conformance of a prepared surface to profile requirements specified by the manufacturer of a protective coating or the coating job specification.

NOTE 2—The peak count/peak density has been shown to be a factor in the performance of various coatings applied to steel. According to research performed by Roper, Weaver and Brandon<sup>6</sup>, an increase in peak count can improve the adhesion of some coatings to the prepared steel, as well as provide greater resistance to corrosion undercutting once the coating becomes damaged in service.

NOTE 3—Optical microscope methods serve as a referee method for surface profile measurement methods A and B. Profile depth designations are based on the concept of mean maximum profile ( $h$  max); this value is determined by averaging a given number (usually 20) of the highest peak to lowest valley measurements made in the field of view of a standard measuring microscope. This is done because of evidence that coating performance in any one small area is primarily influenced by the highest surface features in that area and not by the average roughness.<sup>7</sup>

## 6. Apparatus

6.1 *Method A*—A profile comparator consisting of a number of areas (each approximately one square inch in size), usually side by side, with a different profile or anchor pattern depth. Each area is marked giving the nominal profile depth in mils or micrometres. Typical comparator surfaces are prepared with steel shot, steel grit, or sand or other nonmetallic abrasive, since the appearance of the profile created by these abrasives may differ. The comparator areas are used with or without magnification of 5 to 10 power.

6.2 *Method B*—A depth micrometer fitted with a pointed probe. The probe is typically machined at a 60° included angle with a nominal radius of 50  $\mu$ m and exerting a minimum force of 75 g. The base of the instrument rests on the tops of the peaks of the surface profile while the spring loaded tip projects into the valleys.

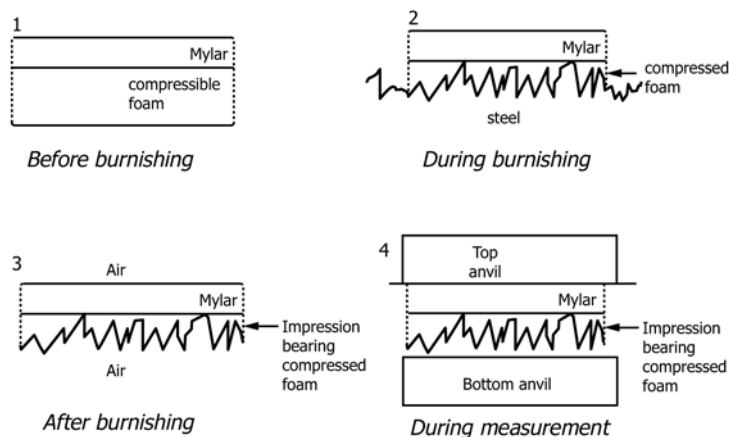
6.3 *Method C*—A replica tape<sup>8</sup> containing a compressible foam attached to a flexible, incompressible plastic substrate of uniform thickness. A burnishing tool, having a spherical rounded end approximately 8 mm (0.3 in.) in diameter, is used to impress the foam face of the tape into the surface to be measured, to create a reverse replica. The thickness of the reverse replica is then measured using a thickness gage specifically designed for use with this replica tape. This sequence of steps is illustrated in Fig. 1.

6.3.1 Thickness gages suitable for use in this application have plane parallel circular contact surfaces with the top contact surface that touches the incompressible polyester side

<sup>6</sup> The Effect of Peak Count or Surface Roughness on Coating Performance, *JPLC* Vol. 22, No. 6, pp 52-64.

<sup>7</sup> John D. Keane, Joseph A. Bruno, Jr., Raymond E. F. Weaver, “Surface Profile for Anti-Corrosion Paints,” Oct. 25, 1976, Steel Structures Painting Council, 4400 Fifth Ave., Pittsburgh, PA 15213.

<sup>8</sup> The sole source of supply of suitable replica tape, Press-O-Film, known to the committee at this time is Testex, 8 Fox Lane, Newark, DE 19711. If you are aware of alternative suppliers, please provide this information to ASTM International Headquarters. Your comments will receive careful consideration at a meeting of the responsible technical committee,<sup>1</sup> which you may attend.



- 1) The tape consists of a compressible foam coated onto an incompressible polyester substrate.
- 2) In use, the tape is compressed (“burnished”) against the roughened surface to be measured.
- 3) After burnishing, the foam retains an impression of the surface.
- 4) Subsequent measurement of the replica’s thickness, minus that of the substrate, yields surface roughness.

**FIG. 1 Illustration of Replica Tape Principle of Measurement**

having a diameter of 6.3 mm (0.25 in.), a closing force of 100 grams-force  $\pm 15$  g and an accuracy of at least  $\pm 5 \mu\text{m}$  (0.2 mils).

6.3.2 Peak density  $Pd$  is extracted from burnished replica tape with an instrument that counts bright spots on a photograph taken by a digital image sensor (camera).

6.4 *Method D*—An apparatus consisting of a portable skidded or non-skidded electronic surface roughness measurement instrument (“tester”) capable of measuring  $Rt$  in compliance with ISO 4287 and  $Rpc$  in compliance with ASME B46.1. The apparatus should have a vertical range of at least  $300 \mu\text{m}$  (12 mil) and permit a sampling length of 2.5 mm (0.1 in.) and an evaluation length of 12.5 mm (0.5 in.) (laboratory experience suggests this vertical range is a practical requirement to meet the provisions of 6.4.1).

6.4.1 The apparatus should include a stylus with a tip radius of  $5 \mu\text{m}$  (0.2 mil), and permit recording of  $Rt$  in the range 10 to  $150 \mu\text{m}$  (0.4 to 6 mil) and  $Rpc$  up to 180/cm (450/in.).

6.4.2 Surface deviations are sensed by the stylus and converted to electrical signals within the device. Internal processing converts these signals into standard surface characterization parameters, which are then displayed or printed.

## 7. Calibration and Standardization

### 7.1 Method A:

7.1.1 Comparators require careful handling and if any surface wear is detected the comparator should be discarded.

### 7.2 Method B:

7.2.1 Before use, each instrument’s accuracy shall be verified by the user in accordance with the instructions of the manufacturer, employing suitable standards and, if necessary, any deficiencies found shall be corrected.

### 7.3 Method C:

7.3.1 Before use, each replica tape micrometer’s accuracy shall be verified by the user in accordance with the instructions of the manufacturer, employing suitable standards and, if necessary, any deficiencies found shall be corrected.

### 7.4 Method D:

7.4.1 Precision reproductions of standard surface profiles such as those used by the manufacturer of the equipment, or described in their operational literature, may be used as calibration standards for the apparatus.

## 8. Preparation of Apparatus

### 8.1 Method A:

8.1.1 Select the comparator standard appropriate for the abrasive used for blast cleaning.

### 8.2 Method B:

8.2.1 Prior to use verify that the gage reads zero by placing it on a piece of plate float glass. Hold the gage by its base and press firmly against the glass. Adjust the instrument to zero if necessary.

### 8.3 Method C:

8.3.1 Confirm that the target profile is within the primary profile measurement range for replica tape of 20 to  $115 \mu\text{m}$ . Grades (thicknesses) of tape permit measurement outside this range, but these additional grades should only be used to check measurements near the ends of the primary range.

### 8.4 Method D:

8.4.1 Set the apparatus to display the chosen parameters in accordance with the manufacturers’ instructions.

8.4.2 The evaluation length should be set to five sampling lengths. The sampling length and evaluation length should be set to 2.5 mm (0.1 in.) and 12.5 mm (0.5 in.), respectively.

8.4.3 The traversing length of the apparatus should be set to include pre-travel and post-travel segments, usually equal to one sampling length at the beginning and one sampling length at the evaluation length. These portions of a traverse are discarded by the instrument in its calculation of surface parameters.

8.4.4 The low frequency (“long wavelength” or “cutoff”) filter should be set to “Gaussian” or “Gaussian 50%.” In general, the default setting will be compliant.

8.4.5 If the apparatus has a high frequency (“short wavelength” or “Ls”) filter, it should be set to “off.”

8.4.6 The apparatus should be adjusted (if necessary) to a deadband width ( $C1 = -C2$ ) in the range 0.5 to 2.0  $\mu\text{m}$  (20 to 80  $\mu\text{in.}$ ). The choice of deadband for profiles as large as those discussed in this standard will have little effect on the measurements. In general, the default setting will be compliant.

8.4.7 The accuracy of the apparatus should be checked regularly using a calibration block available from the equipment manufacturer using their written procedure and at their recommended interval.

## 9. Preparation of the Sample

9.1 Use any metal surface that, after blast cleaning, is free of loose surface interference material, dirt, dust, and abrasive residue.

9.2 Select an area of the surface to be tested that is visibly free from obvious defects such as scratches, deep marks, or other construction or corrosion defects.

9.3 Using a stiff nylon bristle brush, remove any dust or abrasive particles from the surface in the selected sample evaluation area.

## 10. Procedure

10.1 There are four methods to measure the surface profile of the blast-cleaned steel.

10.1.1 **Warning**—Avoid touching abrasive blast cleaned steel with an unprotected hand as moisture, oil, salts, or other contaminants, or combinations thereof, from human skin may transfer to the surface and initiate corrosion.

NOTE 4—SSPC standard SSPC-PA 17 describes a procedure for determining the number of locations to characterize the surface and for determining compliance with specified profile range.

### 10.2 Method A:

10.2.1 Place the comparator directly on the surface to be measured and compare the roughness of the prepared surface with the roughness on the comparator segments. This can be done with the unaided eye, under 5 to 10 power magnification. When using magnification, the magnifier should be brought into intimate contact with the replica, and the depth of focus must be sufficient for the standard and surface to be in focus simultaneously.

10.2.2 Select the comparator segment that most closely approximates the roughness of the surface being evaluated or, if necessary, the two segments to which it is intermediate.

10.2.3 Evaluate the roughness at a sufficient number of locations to characterize the surface as specified or agreed upon between the interested parties. Report the range of results from all locations as the surface profile.

### 10.3 Method B:

10.3.1 To take readings, hold the gage firmly against the prepared substrate. Do not drag the instrument across the surface between readings, or the spring-loaded tip may become rounded leading to false readings.

10.3.2 Measure the profile at a sufficient number of locations to characterize the surface, as specified or agreed upon

between the interested parties. Discard any unusually high instrument readings that cannot be repeated in an area.

10.3.2.1 At each location make ten readings and record the maximum value. Then determine the average for all the location maximum values and report it as the profile height of the surface.

10.3.2.2 An alternate method is to make ten readings at each location and determine the average. Then determine the average for all the locations and report it as the profile height of the surface.

NOTE 5—The ‘average of the location maximums’ procedure in 10.3.2.1 has been shown to produce results that correlate well with methods A, C, and D in this standard, based on theory and experimental data. The alternate ‘average of the averages’ procedure in 10.3.2.2 has been shown to provide lower results than the other methods in this standard, but reduces the impact of outliers that the operator may fail to discard.

### 10.4 Method C:

10.4.1 Follow manufacturer instructions to obtain the first (of two) profile height readings ( $H$ ) and, optionally, the first (of two) peak density ( $Pd$ ) readings.

10.4.2 The average of two “readings” is a “profile measurement.” Manufacturer recommendations provide guidance on whether these two readings should both be obtained with the same tape grade or two different grades.

### 10.5 Method D:

10.5.1 Obtain an initial trace measurement (2 parameters), then four additional trace measurements taken in the compass directions from the original measurement and about 3 cm (1 in.) away for a total of 5 traces, avoiding obvious surface defects.

10.5.2 If the stylus is prevented from making a complete trace due to a physical interference, such as a deep scratch on the surface, move the apparatus to a close adjacent area away from the obvious defect and repeat the trace.

10.5.3 Record the 10 parameters resulting from these five traces (2 parameters per trace).

10.5.4 Calculate the five measurement average for each of the two parameters ( $Rt$  and  $Rpc$ ).

## 11. Report

11.1 At a minimum, the report should contain the following items:

11.1.1 Type of instrument used including manufacturer, model number, serial number, and date of calibration.

11.1.2 Report the number of locations measured, and the approximate total area covered.

11.1.3 For Method A, for each location, the surface profile is determined by comparing the abrasive cleaned surface between two replica plates.

11.1.4 For Method B, the average of the maximum values at each location, or if the alternate method is used, the average of 10 readings at each location and a notation that the alternate method was used.

11.1.5 For Method C, the average of each pair of replica tape readings ( $H$  or  $H_L$ ) and, optionally,  $Pd$ , at each location.

11.1.6 For Method D, the sampling length, evaluation length, and the values of the five trace measurements for each